# **Power MOSFET**

# 100 V, 4 m $\Omega$ , 145 A, Single N-Channel

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS6B03NLWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	100	V
Gate-to-Source Voltage			$V_{GS}$	±16	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	145	Α
Current R <sub>θJC</sub> (Notes 1, 3)		T <sub>C</sub> = 100°C		102	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	198	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		99	
Continuous Drain		$T_A = 25^{\circ}C$	I <sub>D</sub>	20	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		14	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.9	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		2.0	
Pulsed Drain Current	$T_A = 25^{\circ}C$ , $t_p = 10 \mu s$		I <sub>DM</sub>	520	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to + 175	°C
Source Current (Body Diode)			I <sub>S</sub>	160	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 60 A)			E <sub>AS</sub>	180	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.76	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	38	

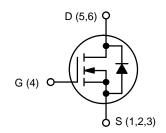
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



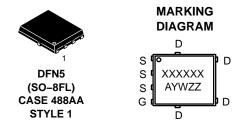
## ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX		
400.1/	4 mΩ @ 10 V	445 A		
100 V	6 mΩ @ 4.5 V	145 A		



**N-CHANNEL MOSFET** 



XXXXXX = 6B03NL (NVMFS6B03NL) or 6B03LW (NVMFS6B03NLWF)

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

# ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				40.9		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$				25	^
		$V_{DS} = 80 \text{ V}$	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 16 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.0		3.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-6.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}$ $I_{D} = 20 \text{ A}$ $V_{GS} = 4.5 \text{ V}$			3.3	4.0	
					4.8	6.0	mΩ
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, V}_{DS} = 25 \text{ V}$			5320		pF
Output Capacitance	C <sub>OSS</sub>				1850		
Reverse Transfer Capacitance	C <sub>RSS</sub>				110		
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 50 \text{ V}; I_D = 50 \text{ A}$			70.7		- nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				9.4		
Gate-to-Source Charge	$Q_{GS}$				17.3		
Gate-to-Drain Charge	$Q_GD$				7.4		
Plateau Voltage	$V_{GP}$				3.3		V
SWITCHING CHARACTERISTICS (Note 5	)						
Turn-On Delay Time	t <sub>d(ON)</sub>				19.9		
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 50 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 2.5 \Omega$			181.7		ns ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				28.7		
Fall Time	t <sub>f</sub>				152.4		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	$V_{SD}$	Ic = 50 A	$T_J = 25^{\circ}C$		0.81	1.2	V
			T <sub>J</sub> = 125°C		0.7		v
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 25 \text{ A}$			64.7		ns
Charge Time	t <sub>a</sub>				33.4		
Discharge Time	t <sub>b</sub>				31.8		
Reverse Recovery Charge	Q <sub>RR</sub>				99		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS

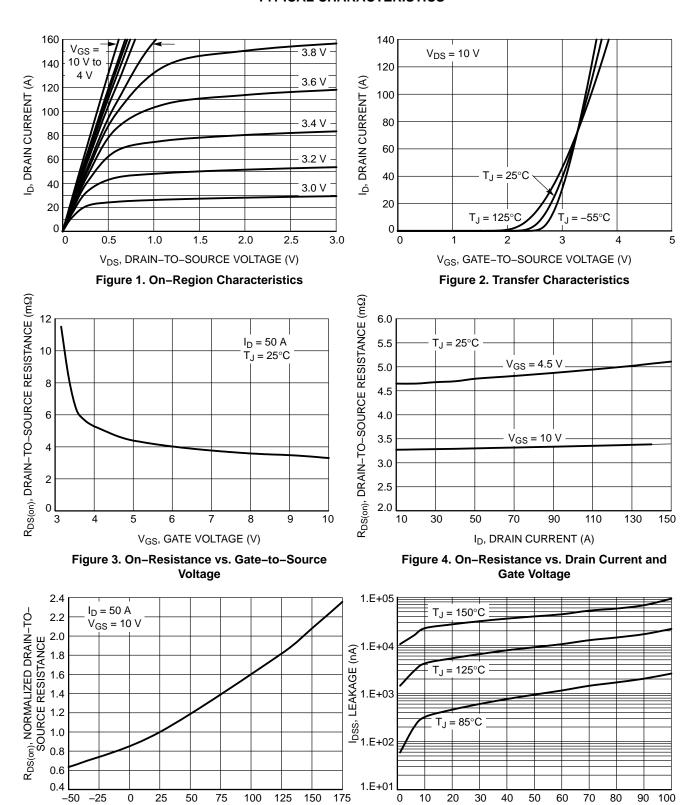


Figure 5. On–Resistance Variation with Temperature

T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

## **TYPICAL CHARACTERISTICS**

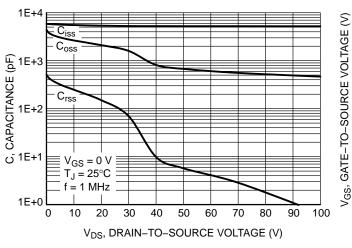


Figure 7. Capacitance Variation

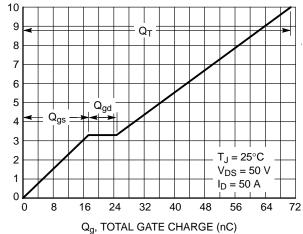


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

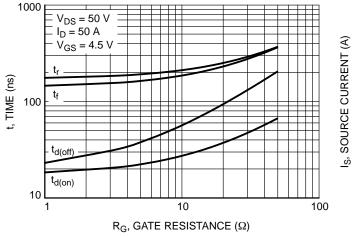


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

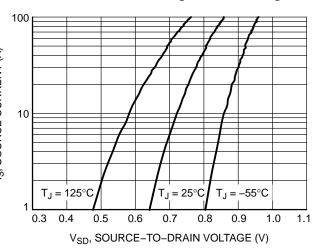
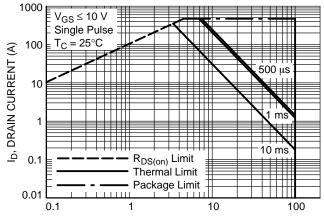


Figure 10. Diode Forward Voltage vs. Current



V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 11. Maximum Rated Forward Biased Safe Operating Area

### TYPICAL CHARACTERISTICS

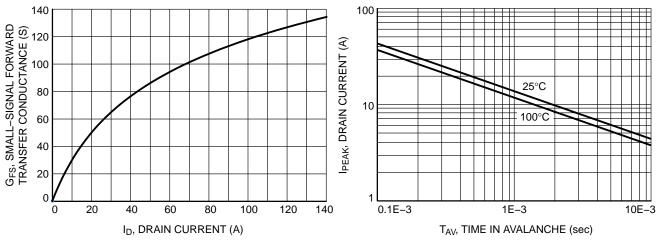


Figure 12. G<sub>FS</sub> vs. I<sub>D</sub>

Figure 13. I<sub>PEAK</sub> vs. T<sub>AV</sub>

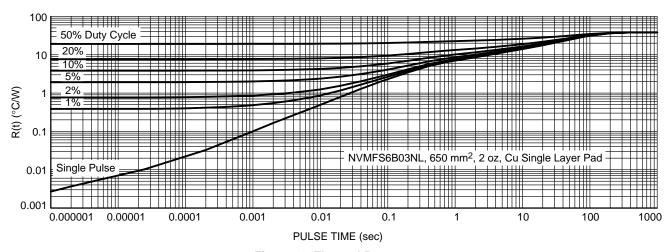


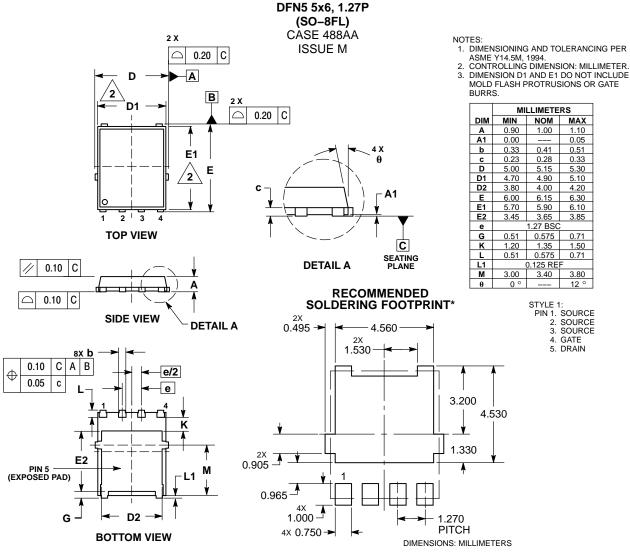
Figure 14. Thermal Response

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS6B03NLT1G	6B03NL	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS6B03NLWFT1G	6B03LW	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS6B03NLT3G	6B03NL	DFN5 (Pb-Free)	5000 / Tape & Reel
NVMFS6B03NLWFT3G	6B03LW	DFN5 (Pb-Free, Wettable Flanks)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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